

Microelectronics

Introduction to the IC technology

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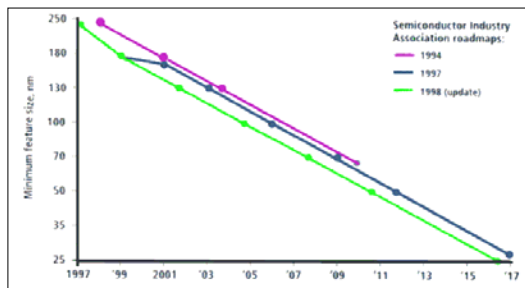
11 September, 2002

Integrated circuits

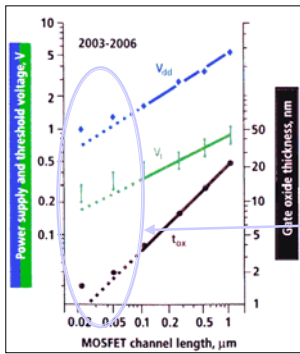
Development is controlled by the „roadmaps“. Self-fulfilling predictions *for the tendencies of development.*

1. Roadmap requirements for IC fabrication			
Year	1997-2001	2003-2006	2009-2012
Semiconductor technology needs			
Feature size, nm	250-150	130-100	70-50
Millions of transistors per square centimeter	4-10	16-39	84-180
Number of wiring layers	6-7	7-8	8-9
Assembly and packaging technology needs			
Pad pitch, nm	250-150	130-100	70-50
Cents per pin	0.7-2.3	0.5-1.8	0.4-1.3
Power, W	1.2-61	2-96	2.8-109
Die size, mm ²	50-385	60-520	70-750
Performance, MHz	200-730	530-1100	840-1830
Voltage, V	1.2-2.5	0.9-1.5	0.5-0.9
Pin count	100-900	160-1476	260-2690

Source: National Technology Roadmap for Semiconductors



Expected decrease in line width

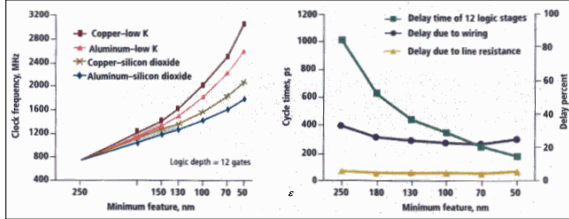


Oxide thickness, Power supply and threshold voltage tendencies

Approaching physical limits

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Interconnect resulted delay has to be decreased. The delay is proportional to the R and C of the interconnect lines. (see later)

Decreasing R: *copper* instead of *Al*

Decreasing C: lower ϵ insulator instead of SiO_2

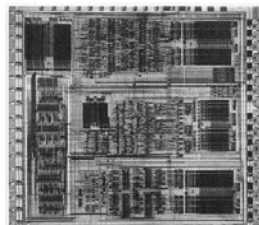
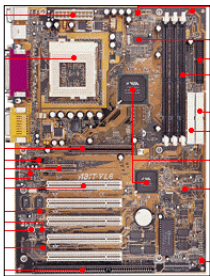
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$$\epsilon_r |_{\text{SiO}_2} = 3.9$$

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VLSI rudiments

Packaged integrated circuits on a PCB
(Computer motherboard)

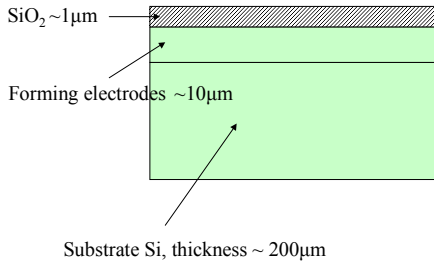


Microprocessor *chip* layout

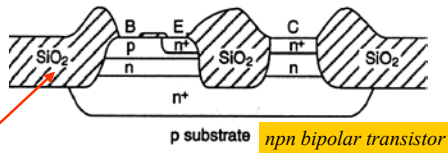
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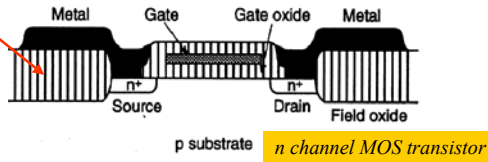
Cross-section of a chip



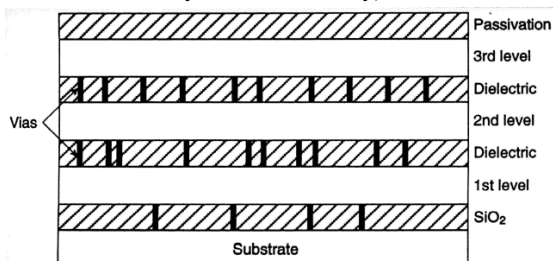
Cross-section of transistors



Isolation



Cross-section of a 3 layer interconnect (5-6 metal layers are usual today)



Forming the vertical structure: technology
Forming the horizontal structure: design
separated in space and time

Their relationship is given by the **Design rules** referring to the technology.

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Fabricating VLSI circuits: the *planar technology*

Planar: refers to the fact that all the circuits are fabricated in a plane

Base: *the silicon single crystal, fabricated in bars*. The 2-12" diameter large, about 0.25 mm thick *wafers* are sliced from these. On one wafer several thousands of IC chips or dies are fabricated at the same time



Finished wafers before dicing

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The group of wafers processed together: a *party*



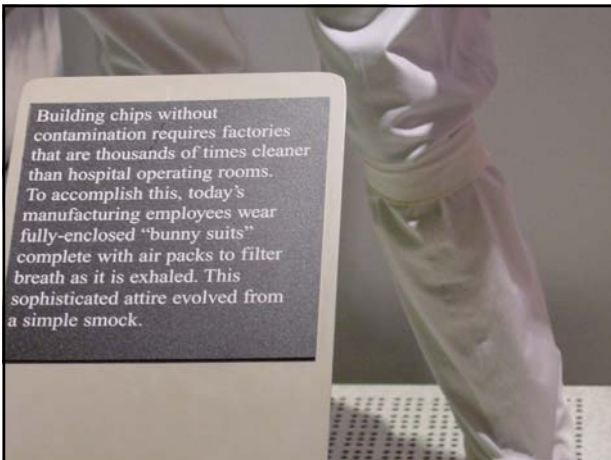
A party is being put into a furnace



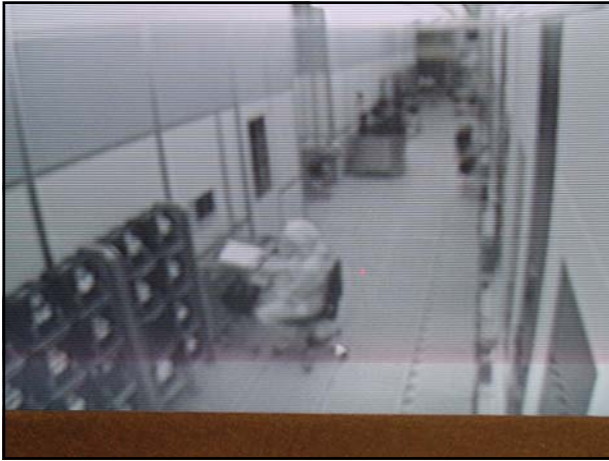
Very high cleanness requirements: *clean rooms*

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Microelectronics fabrication process

A sequence of

- doping,
- deposition
- lithographic

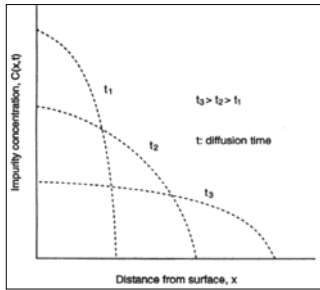
process steps

Doping procedures: aims at changing the doping at certain volumes of the semiconductor

methods:

- diffusion
- ion implantation

Diffusion: as a result of the elevated temperature (about 1000°C) the dopant atoms from the ambient diffuse into the silicon at the locations where this is not prevented by SiO₂. The **silicon dioxide „masks“** against the diffusion.

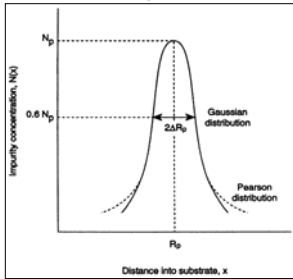


Doping profile after diffusion

$x = 0$ is the surface, x points perpendicularly inwards the Si

- The doping of the surface layers is stronger
- Side diffusion has to be considered

Ion implantation: shooting accelerated ions into the Si



Doping profile after ion implantation

$x = 0$ is the surface, x points perpendicularly inwards the Si

Advantages of ion-implantation over the diffusion

- higher accuracy,
- low temperature operation
- no size difference between the mask and the doped surface area

disadvantages:

- damaged crystal structure
- less productive than diffusion

Layer deposition steps

Chemical or physical methods to produce contiguous layer on the surface

Oxidation

Production of SiO_2 layer on the surface of Si in oxygen ambience at about 1000°C temperature. The SiO_2 layer on the surface is perfect conductor, behaving selectively against chemicals

The double role of SiO_2

1. Fabrication technological (masks)
2. Electronic
 - insulation between the surface layers (Thick oxide)
 - dielectric of MOS transistors (thin oxide)

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Epitaxial layer deposition

Forming of a Si layer on the surface that continues the single crystal structure, but e.g. with lower doping density 1200°C temp.process.

CVD (Chemical Vapor Deposition)

deposition of amorphous or polycrystalline Si onto the surface

PVD (Physical Vapor Deposition)

For the deposition of metal layers (evaporation or sputtering)

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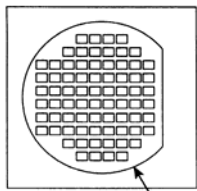
Steps of the lithography

To form the patterning in the SiO_2

Steps

- photoresist deposition on the surface
- patterning
- oxide etching

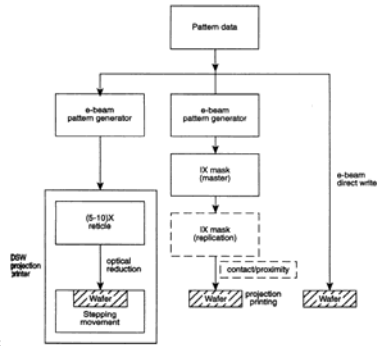
Chip patterns: **reticle**,
wafer patterns **masks**.



- Photo-technical steps
- Illumination through the masks
- The mask patterns imaged into the SiO_2
- New masks for all the technological steps → a technology is defined by a **series of masks**
- Pattern data are produced by CAD programs

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Possibilities for wafer patterning

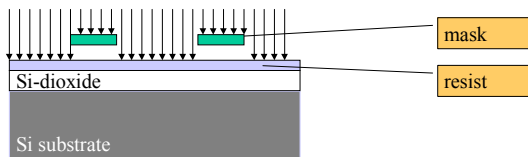


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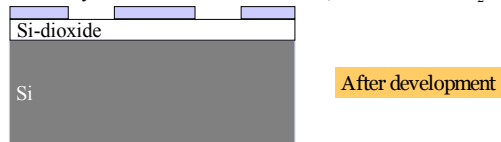
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Photo-lithographic steps

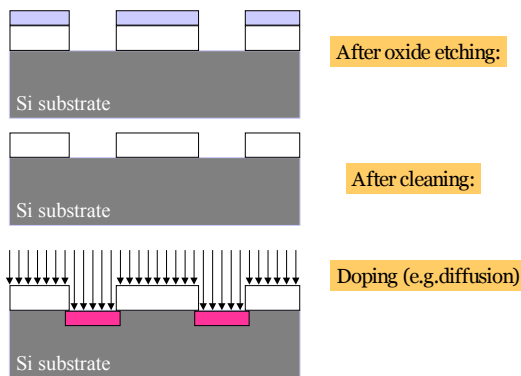
Patterning the SiO₂



At the illuminated areas the photo-resist polymerises, → becomes resistive against certain chemicals, so that the mask pattern may be transmitted into the resist, later into the SiO₂



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The SiO₂ pattern masks against the diffusion

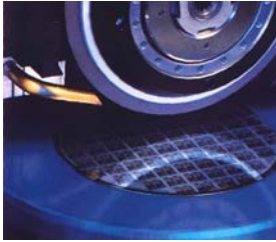
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Individual steps

Wafer operations are group operations → cheap.
Individual operations are expensive, should be minimised.
Most of the testing steps have to be carried out on the wafer, the bad chips must not be packaged

Dicing

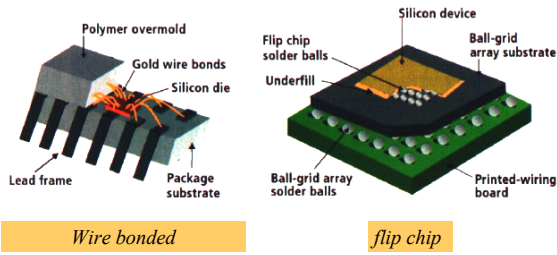


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Packaging

The most frequent packaging methods

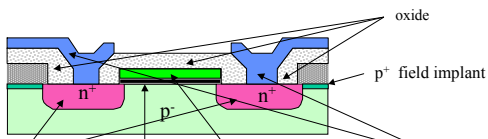


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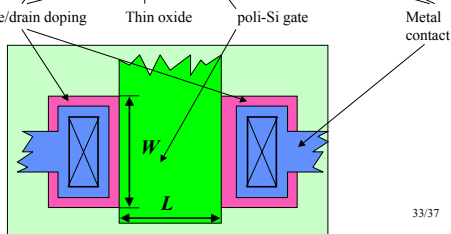
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MOS IC fabrication steps

The structure:

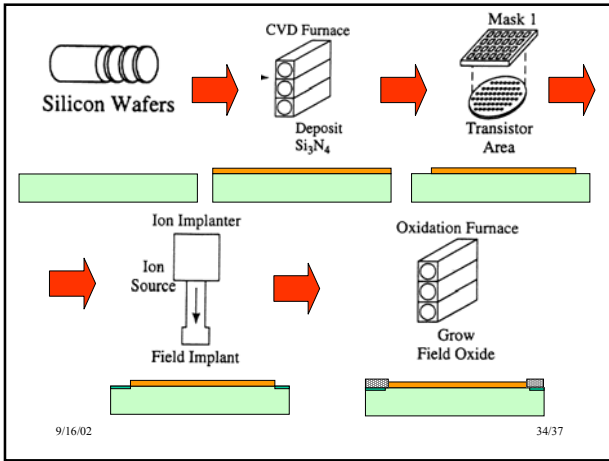


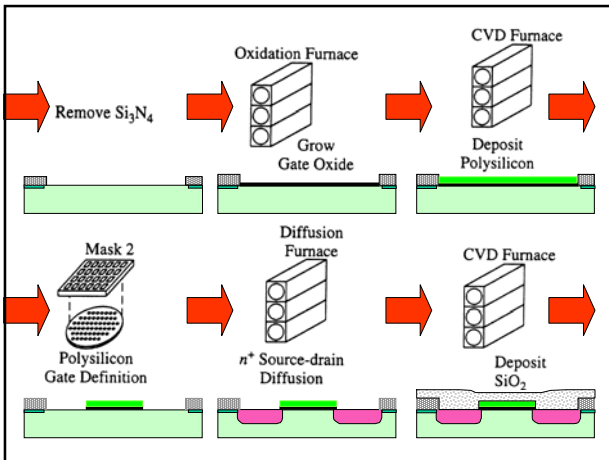
Layout:

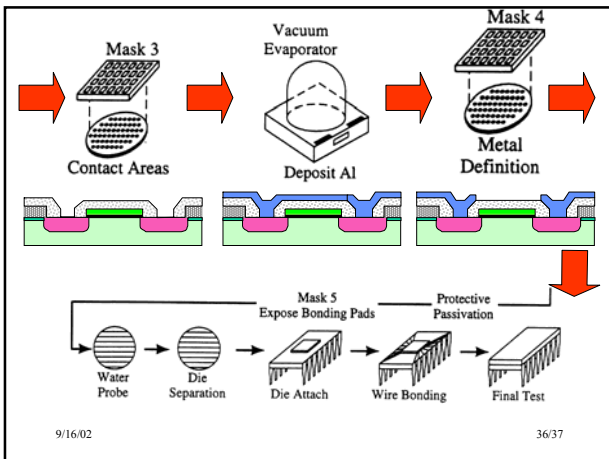


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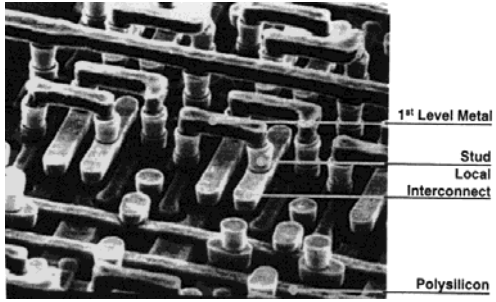
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*Example: detail of a fabricated IC,
electron-microscopic image*



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